

LAD Dehosition Flocess For Enhanced Properties Of Metal Films\* Michael Rumer et al.

Appln. No.: 09/675,627



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Ti <0002> Grain Performanc vs. H<sub>2</sub> Amount Introduced in Ti Module During Burst Step

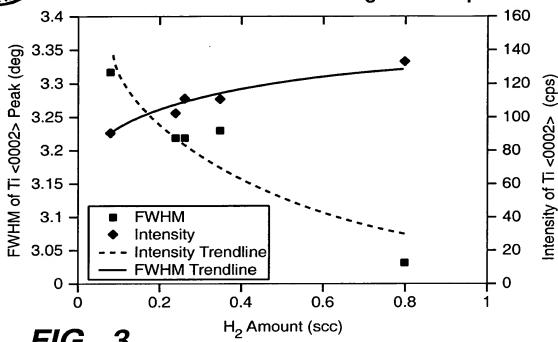


FIG.\_3

TiN <111> and AI <111> Grain Performance vs. H<sub>2</sub> Amount Introduced in Ti Module During Burst Step

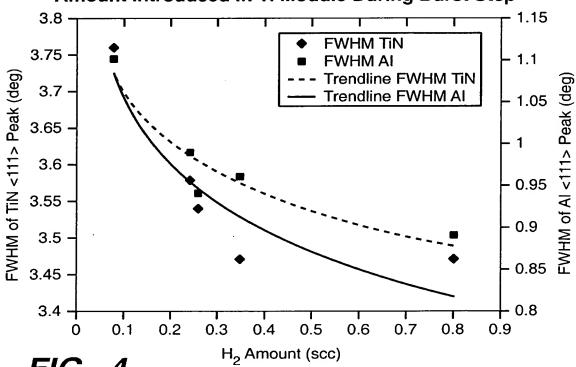


FIG.\_4



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## FWHM of AI <111> P ak vs. Thickness of Ti Underlayer

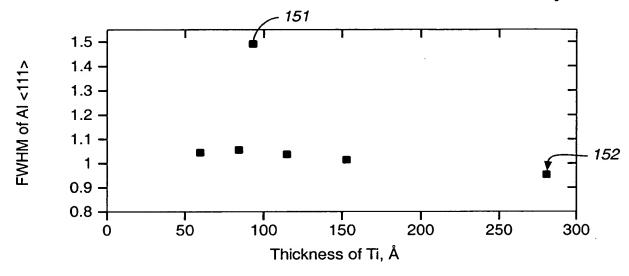


FIG.\_5a

## Intensity of AI <111> Peak vs. Thickness of Ti Underlayer

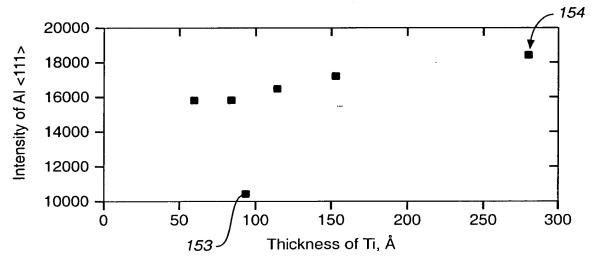


FIG.\_5b